

ReRAM ASIC Compute Crossbar

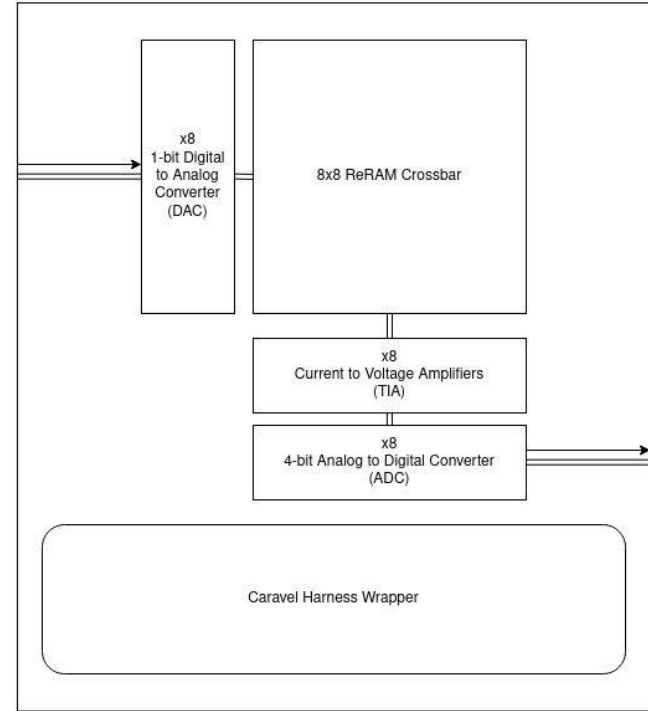
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Advisors and clients: Dr. Duwe and Dr. Wang

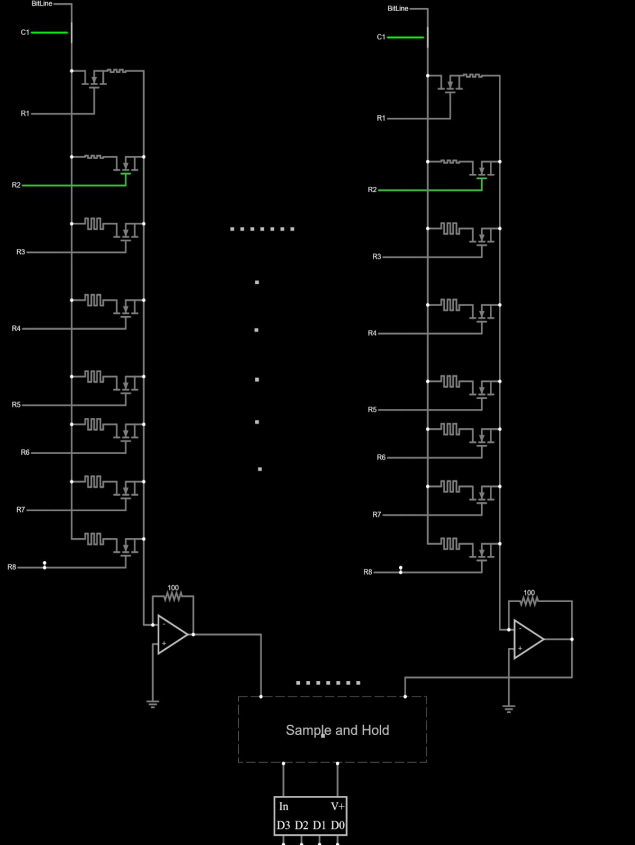
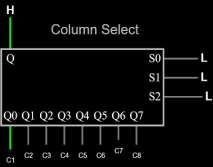
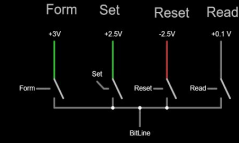
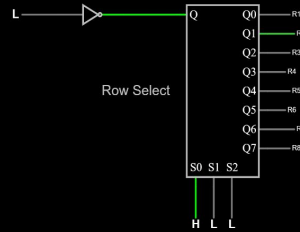
Project Overview

Design a test vehicle for Resistive Random-Access Memory(ReRAM) crossbar for proof of concept

- Utilize open-source design tools
- Submit fabrication application through Efabless shuttle program
- Create bring up plan to test device
- Create documentation for open-source tools for future users



Detailed Design and Visuals

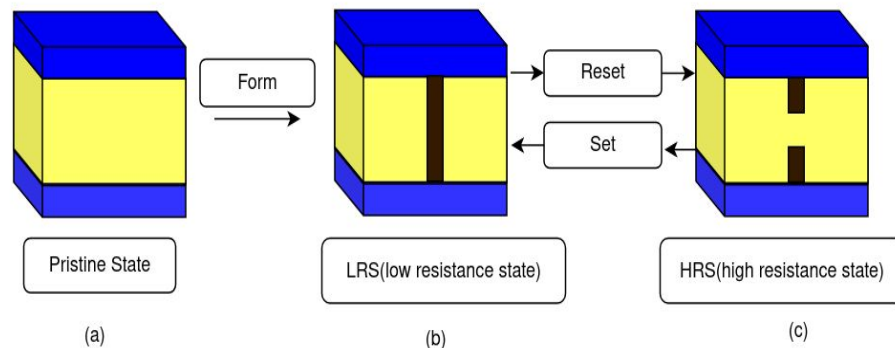


ReRAM cell states

The conductance of a ReRAM cell is dependent on whether the cell is in a LRS(low resistance state) or in a HRS(high resistance state).

- A LRS is viewed as a “digital 1”
- A HRS is viewed as a “digital 0”.

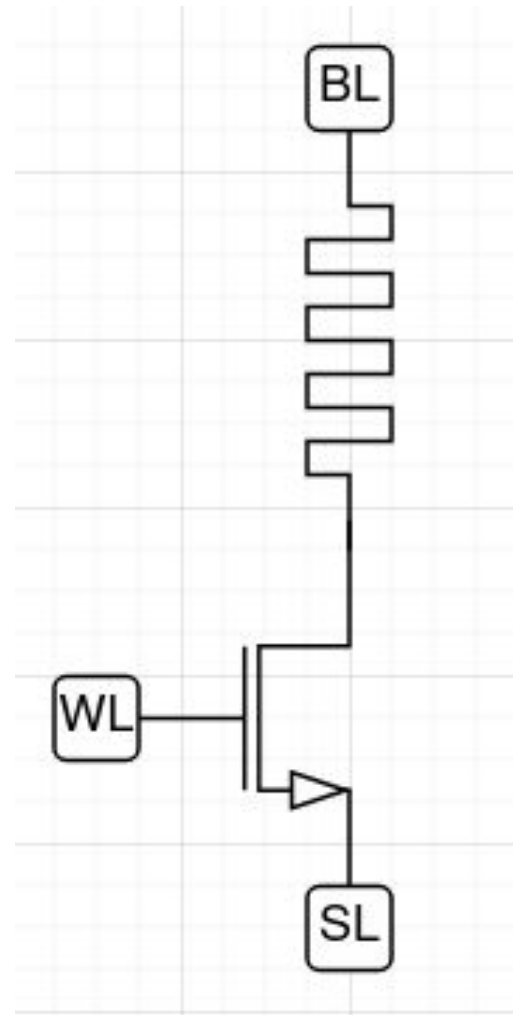
All ReRAM cells start in a pristine state and must be formed into a LRS initially. After the initial form the cell can be set and reset as needed to switch between a digital 1 or 0. This process is illustrated in the image below.



Individual ReRAM cell

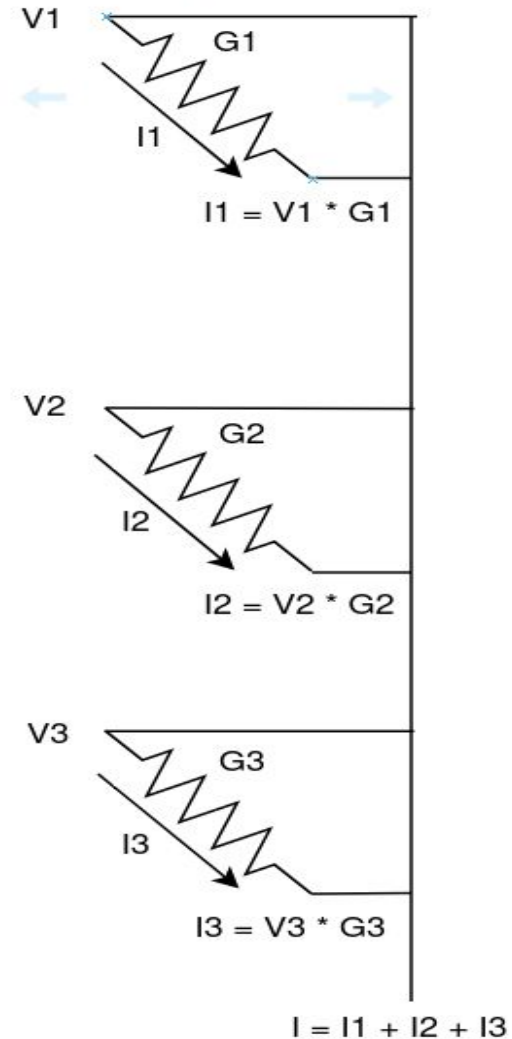
An individual ReRAM cell is shown

- Crossbar will consist of an 8x 8 array of these
- Each contains one resistor and one transistor
 - Referred to as the 1T1R architecture
- Wordline(WL) is connected to a logic analyzer
 - Will determine whether or not the cell is on or off
- Bitline(BL) is connected to the DAC
 - This is where the necessary voltage will be passed into the cell
- SourceLine(SL) is where the current will accumulate to be output

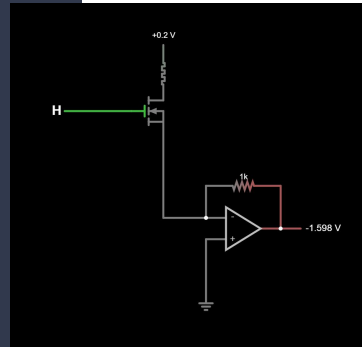
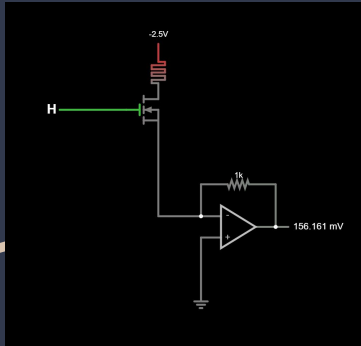
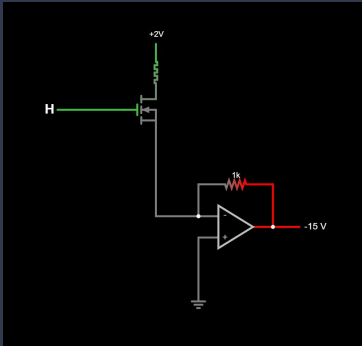
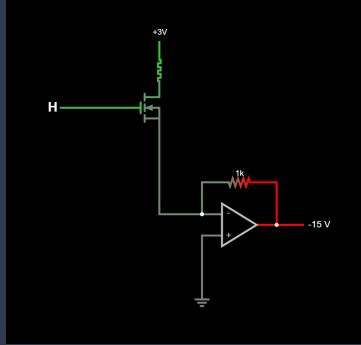
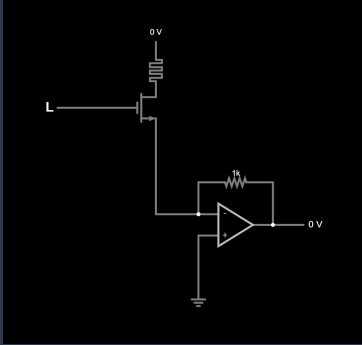


MAC Operation

We will use these cells to perform a MAC operation. This operation is illustrated in the image shown where the input voltages, V_1, V_2 and V_3 are multiplied by the conductances, G_1, G_2 , and G_3 of the ReRAM and the resulting currents are then summed down along the column to create one output.



Functionality



1. Initial state
 - High resistance, low conductance
2. Form
 - Power bit $\sim 3.3\text{V}$ and word line $\sim 1.8\text{V}$ for 1ms
 - Forms filaments that will be broken and reformed during Sets and Resets
 - After form memristor is in a "high" state
3. Set
 - Power bit $\sim 2.5\text{V}$ and word line $\sim 1.8\text{V}$ for 1ms
 - Sets the memristor to its "high" state
4. Reset
 - Power source $\sim 2.5\text{V}$ and word line $\sim 1.8\text{V}$ for 1ms
5. Read
 - Power bit $\sim 0.2 - 0.4\text{V}$ and word line $\sim 2.5\text{V}$
 - Allows for reading of memristor state through current analysis but doesn't change memristor state quickly

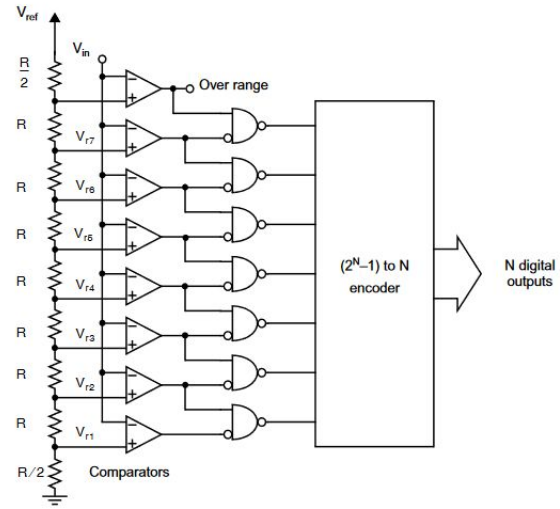


Fig. 17.24 A 3-bit flash A/D converter.